



US00D759603S

(12) **United States Design Patent**
Saito et al.

(10) **Patent No.:** **US D759,603 S**
(45) **Date of Patent:** **** Jun. 21, 2016**

(54) **CHAMBER OF CHARGED PARTICLE BEAM
DRAWING APPARATUS**

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(**) Term: **14 Years**

(21) Appl. No.: **29/514,862**

(22) Filed: **Jan. 16, 2015**

Related U.S. Application Data

(63) Continuation-in-part of application No. 29/479,498,
filed on Jan. 16, 2014, now Pat. No. Des. 722,298.

Foreign Application Priority Data

Jul. 17, 2013 (JP) 2013-016242

(51) **LOC (10) Cl.** **13-03**

(52) **U.S. Cl.**
USPC **D13/182**

(58) **Field of Classification Search**

USPC D13/101, 123, 182; 250/396 R, 396 ML,
250/398, 400, 492.1, 492.2, 492.21, 492.22,
250/492.3; 430/4, 5, 24, 25, 30, 269, 396
CPC ... H01J 37/153; H01J 37/141; H01J 37/3174;
H01J 37/3175; H01J 37/12; H01J 37/045;
H01J 37/3007; H01J 2237/31715; H01J
2237/31752; G21K 1/08; G21K 1/087;
G21K 1/093; G21K 5/04; G21K 5/10; G21K
2201/00; G21K 2201/068; B29C 67/0066
See application file for complete search history.

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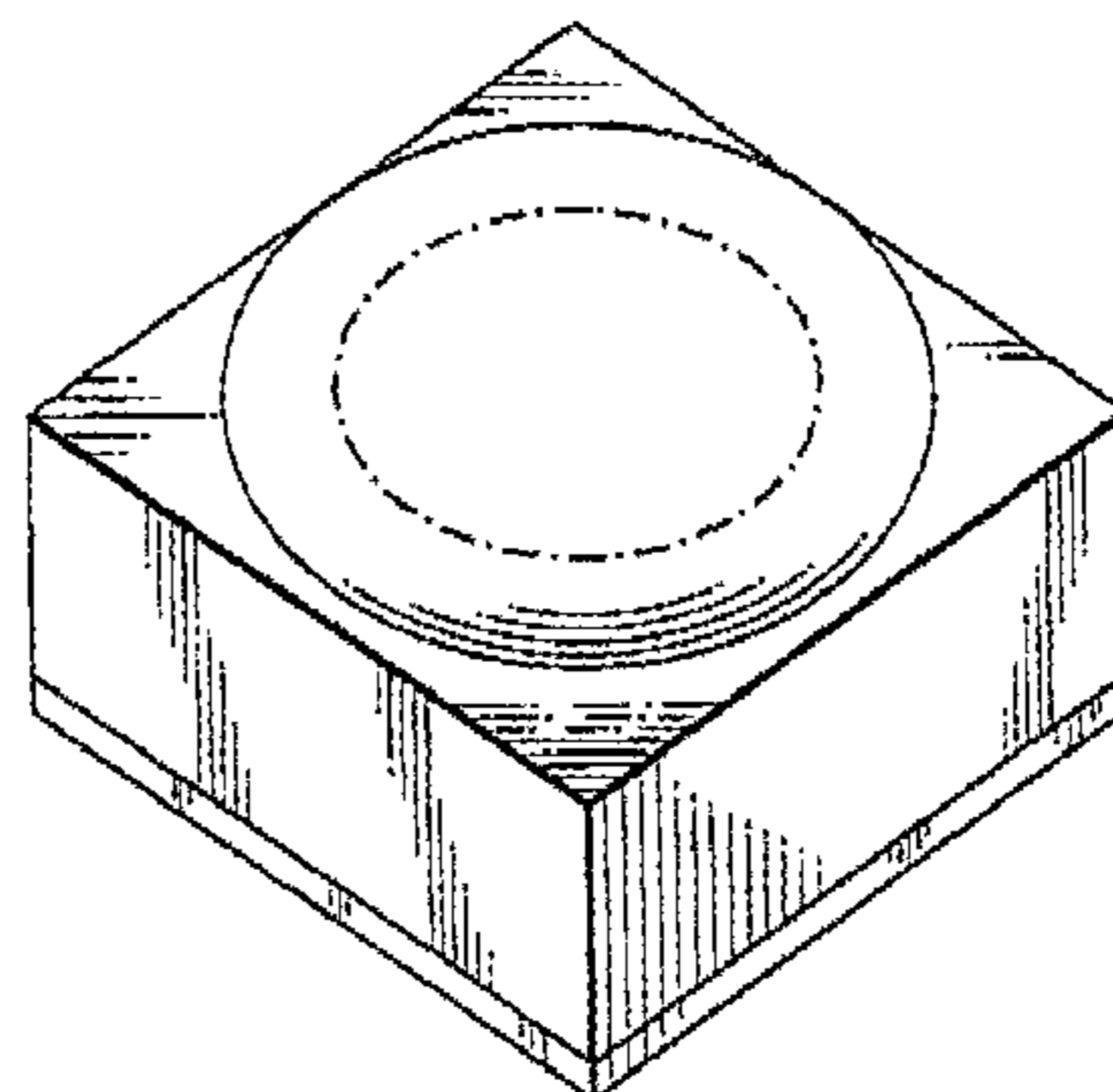
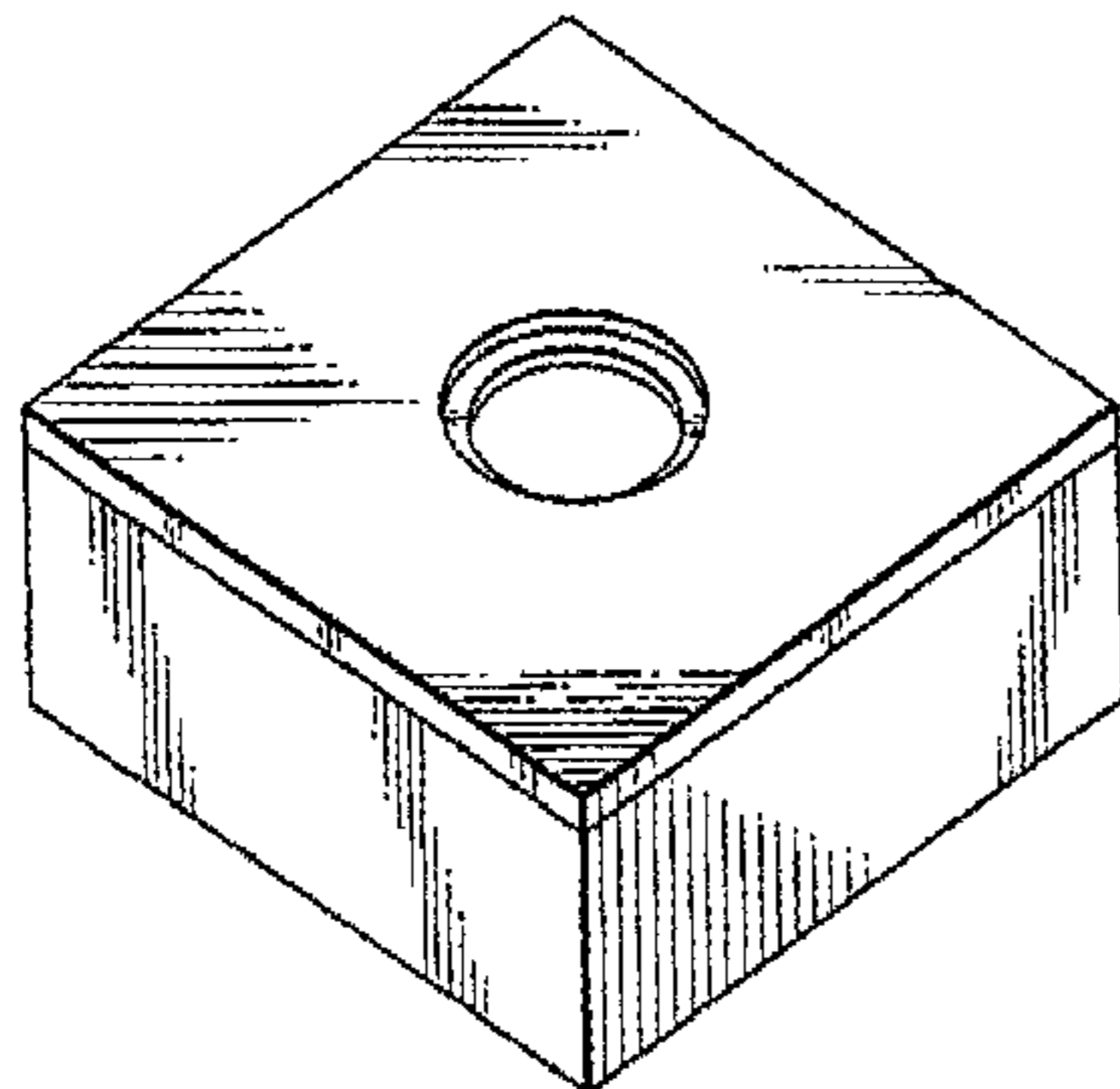
(57) **CLAIM**

The ornamental design for a chamber of charged particle
beam drawing apparatus, as shown and described.

DESCRIPTION

FIG. 1 is a top perspective view of a chamber of charged
particle beam drawing apparatus showing our new design;
FIG. 2 is a bottom perspective view thereof;
FIG. 3 is a front view thereof;
FIG. 4 is a right side view thereof, the left side view being a
mirror image;
FIG. 5 is a top plan view thereof;
FIG. 6 is a bottom plan view thereof;
FIG. 7 is a cross-sectional view taken along a line 7-7 in FIG.
3; and,
FIG. 8 is a cross-sectional view taken along a line 8-8 in FIG.
3.
The dot-dash lines indicate the boundary between the claimed
portion and unclaimed portion.

1 Claim, 4 Drawing Sheets



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FIG. 1

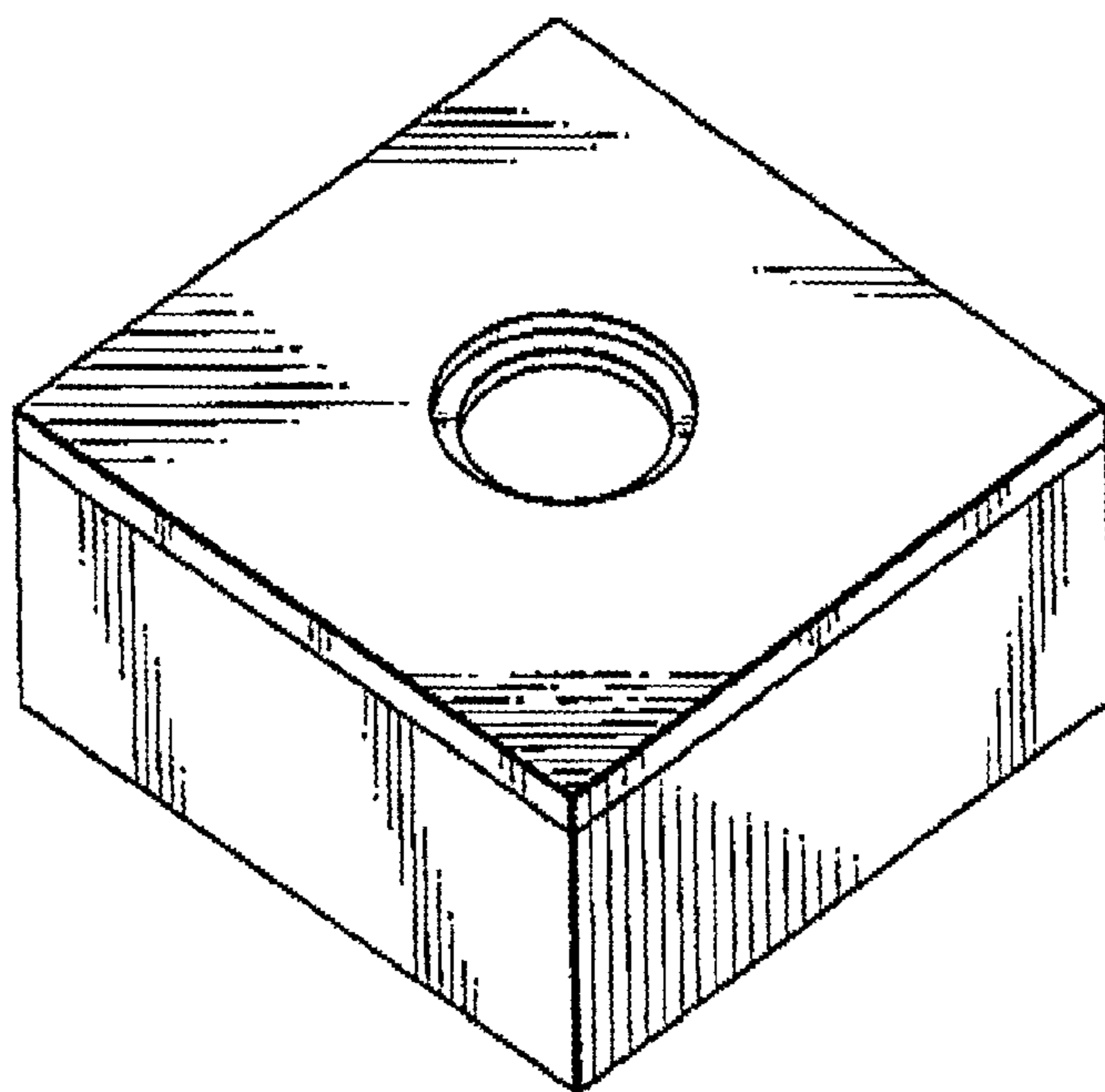


FIG. 2

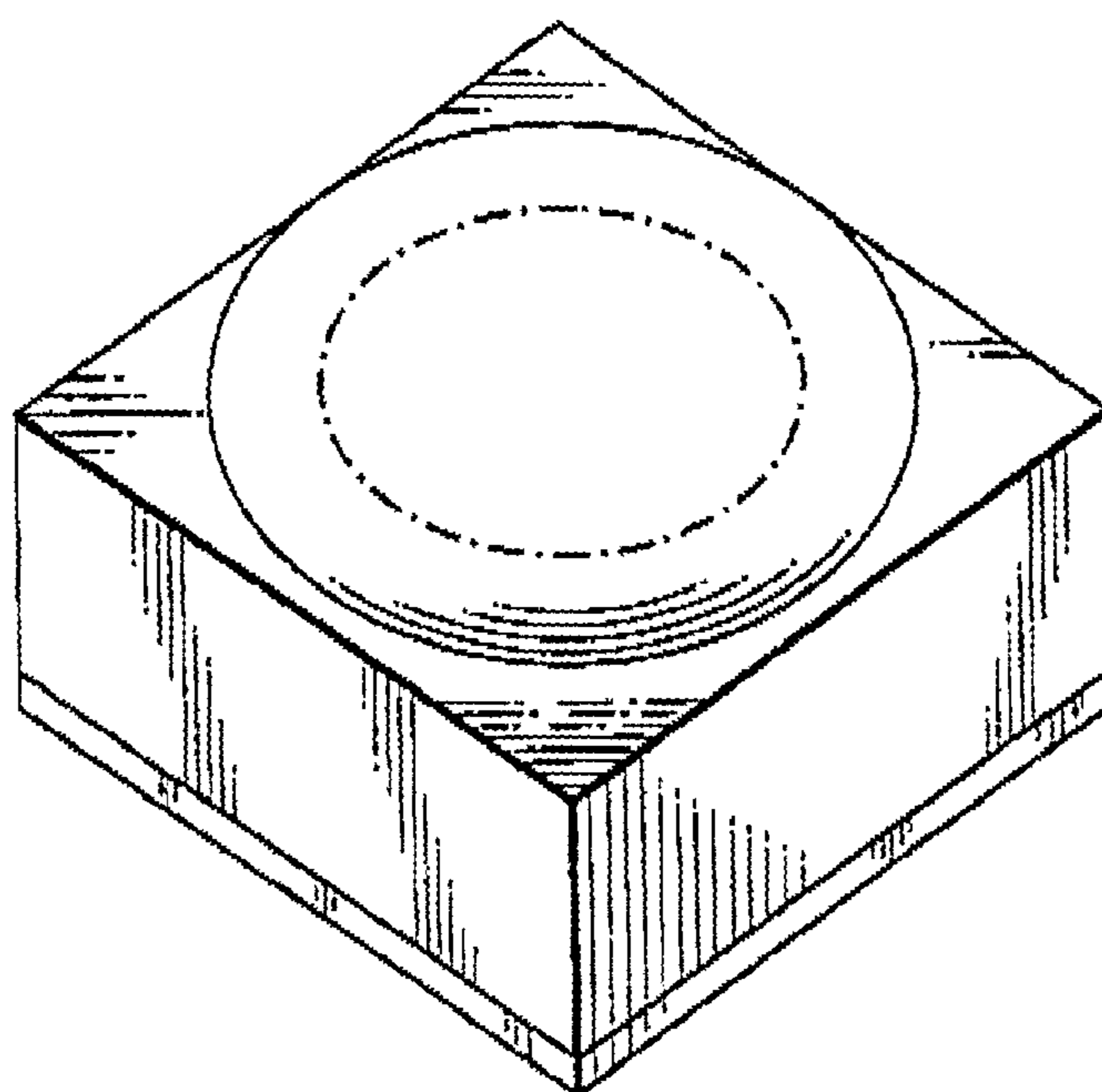


FIG. 3

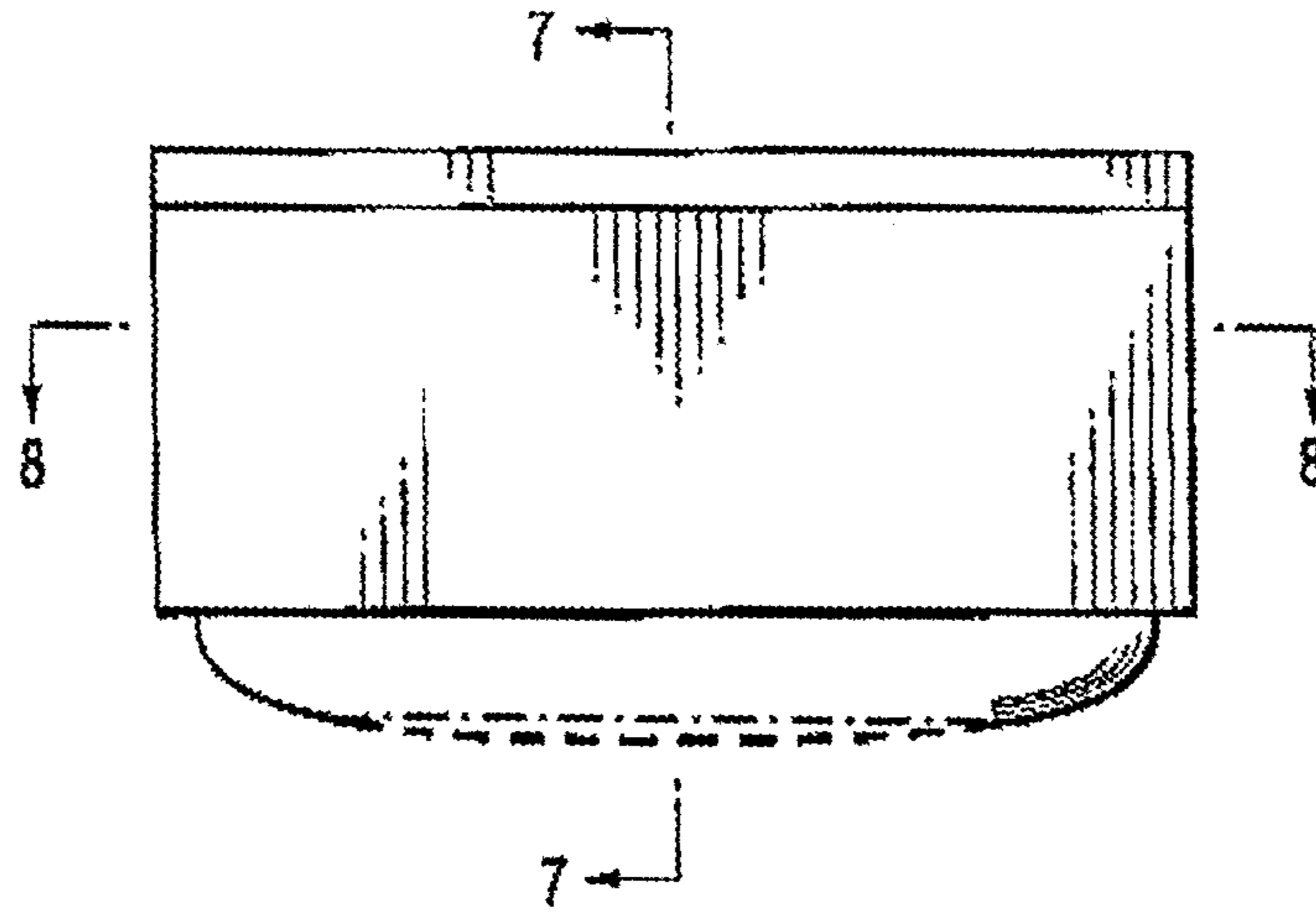


FIG. 4

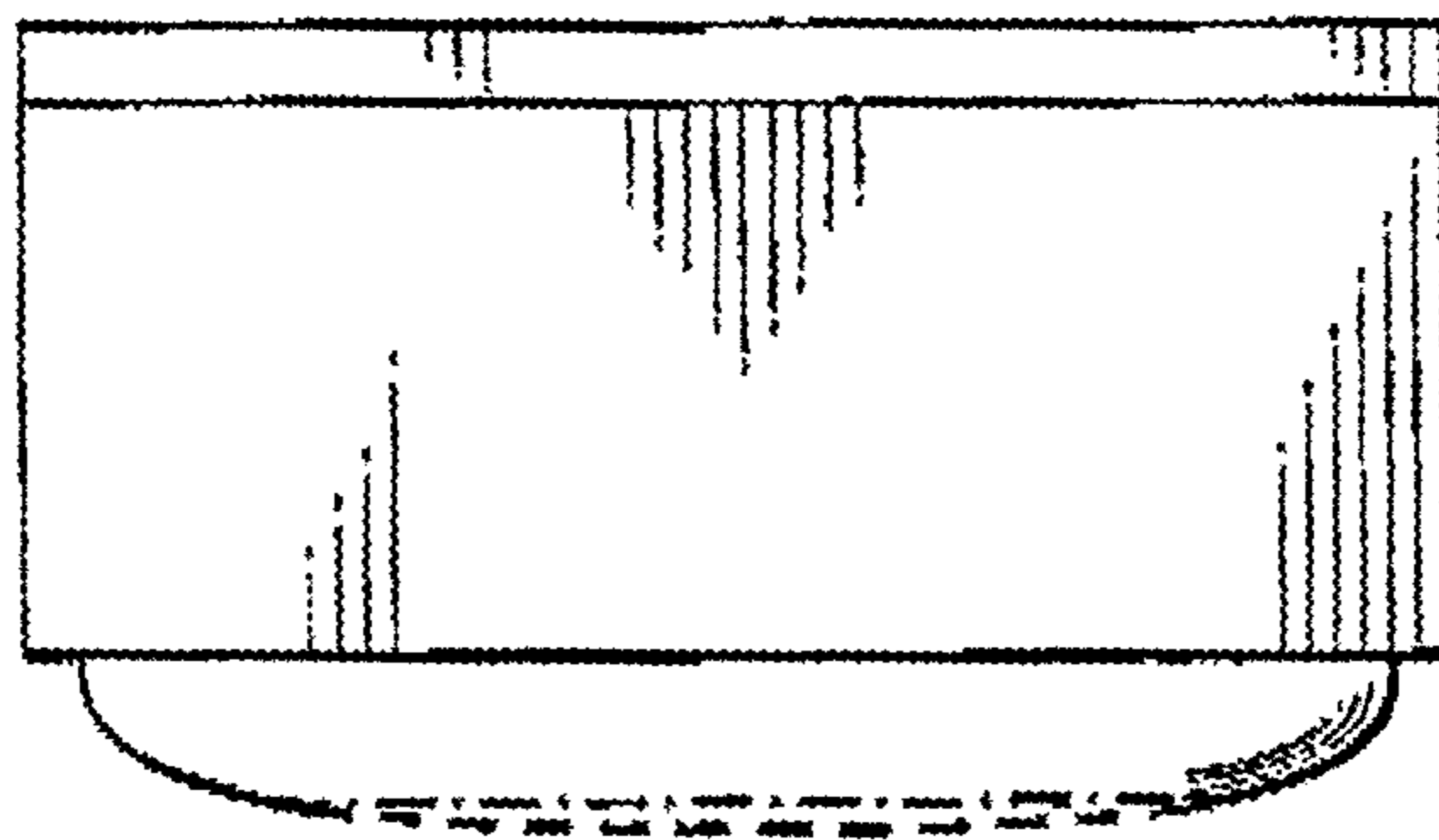


FIG. 5

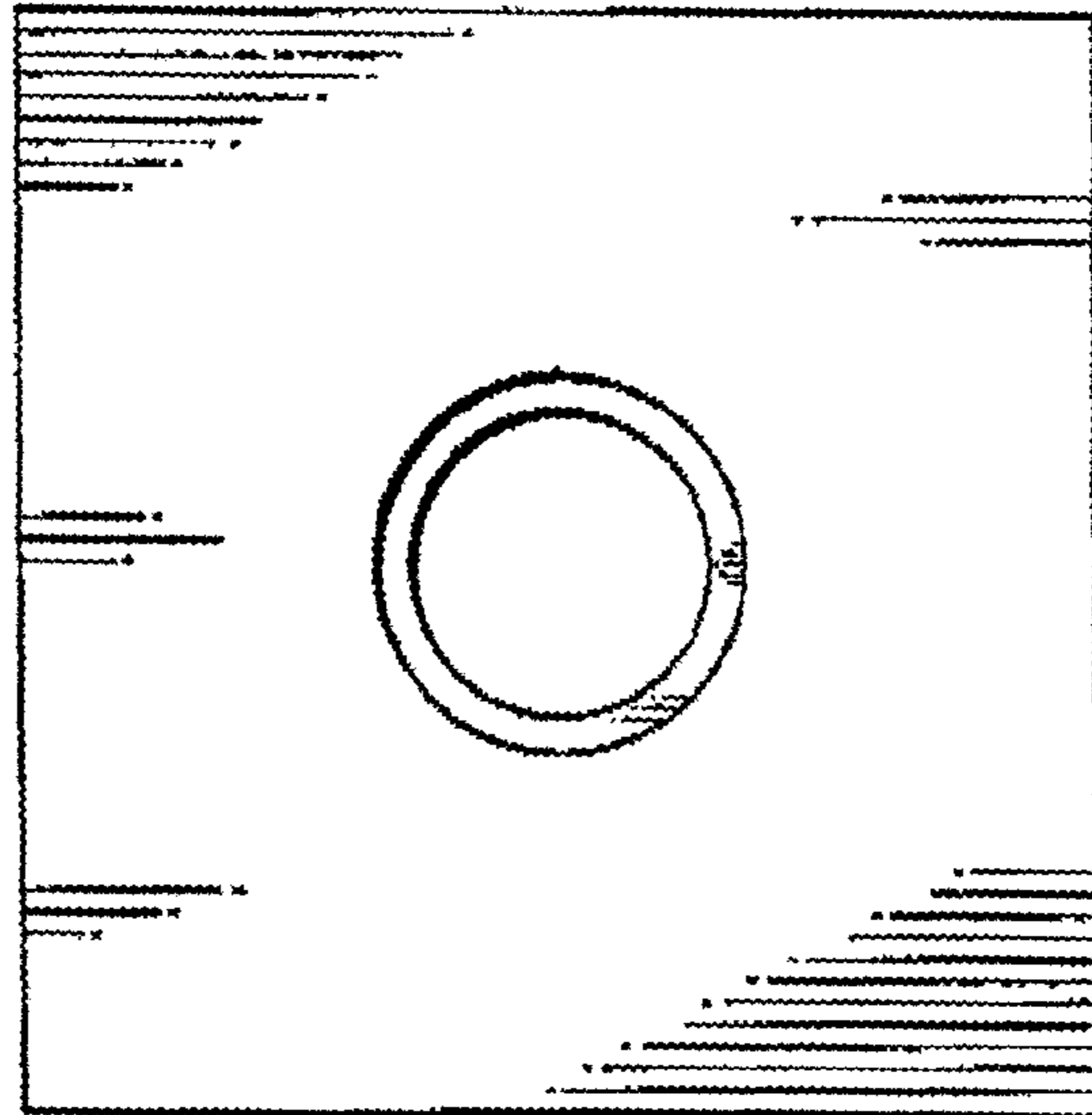


FIG. 6

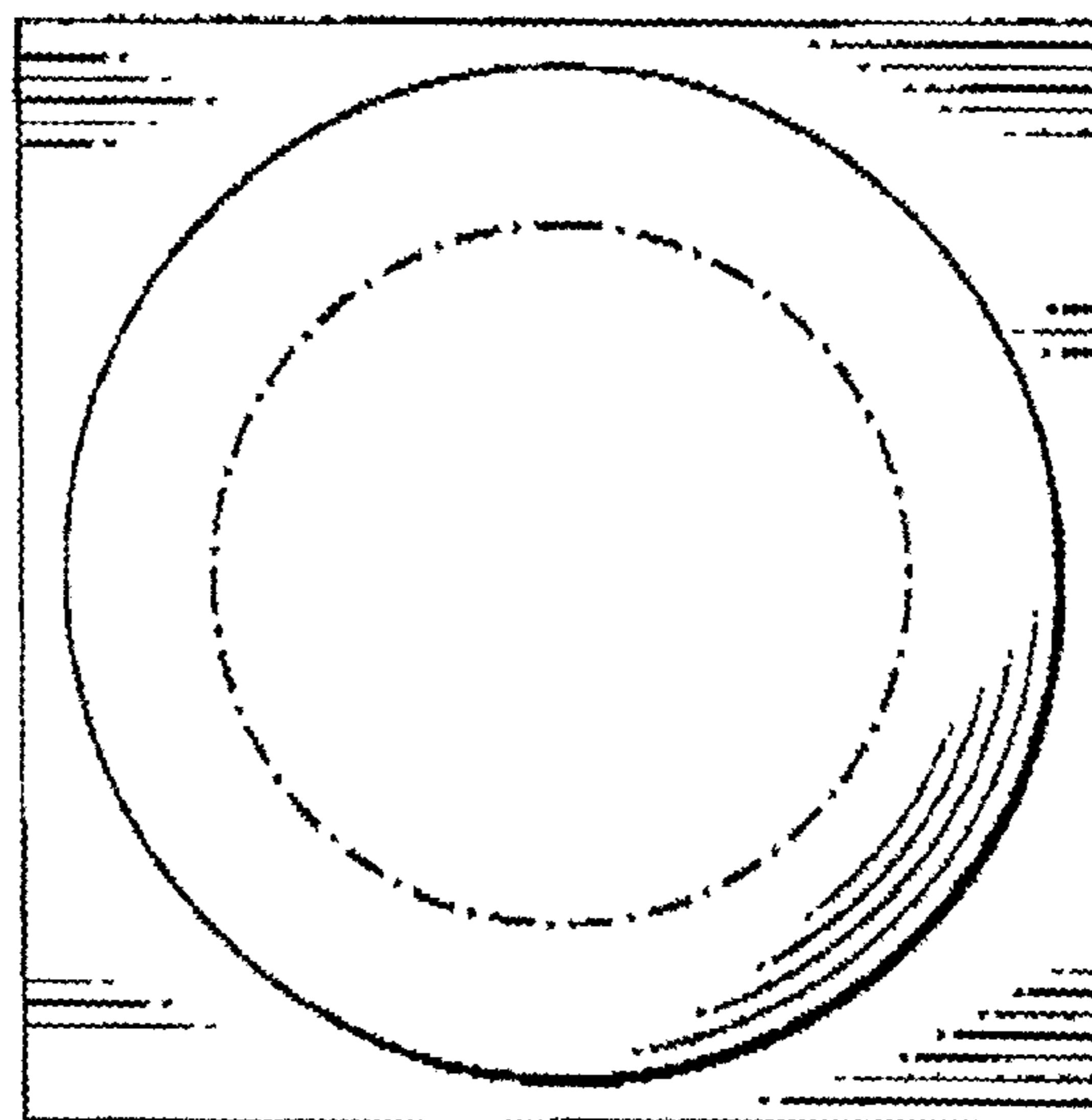


FIG. 7

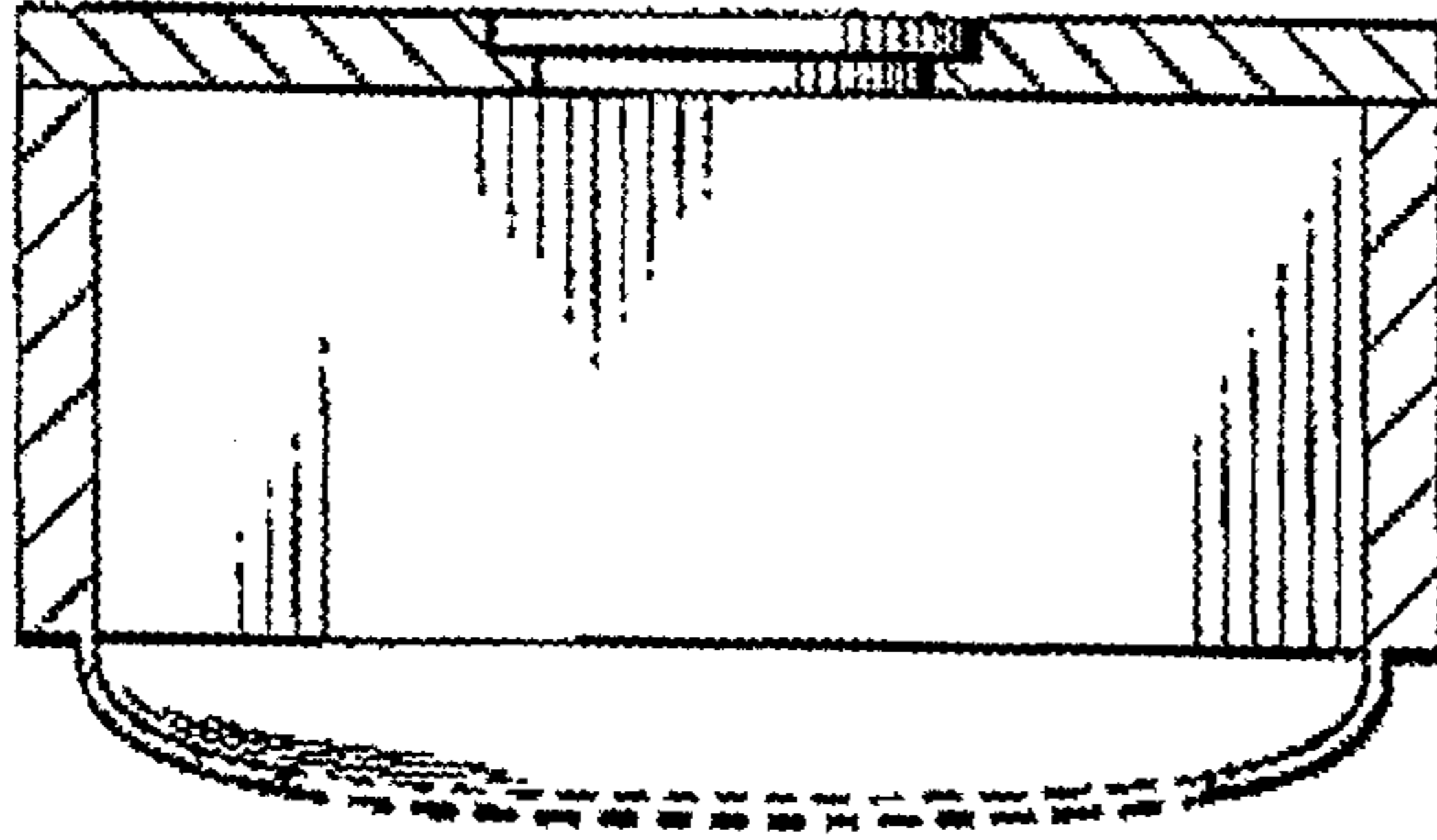


FIG. 8

